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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

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| Inventor(s): | Ying EE Yip et al. | Examiner: | Holder, Regina Neal |
| Serial No.: | 09/851,767 | Group Art Unit: | 2651 |
| Filed: | May 9, 2001 | Docket No.: | STL9663 |
| Title: | Pattern-Based Defect Description Method | | |

Mail Stop Non-Fee Amendment
Commissioner For Patents
PO Box 1450
Alexandria, VA 22313-1450

AMENDEMNT

Madam:

In response to the Office Action mailed May 7, 2003, please amend the present application as follows and consider the following remarks.

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Technology Center 2600